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Rossig, C.; Herrmann, R.; Hotter, M.;

Image Processing and Its Applications, 1997., Sixth International Conference on , Volume: 1 , 14-17 July 1997

Page(s): 394 -398 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(604 KB\)\]](#) **IEE CNF**

2 Registration and statistical analysis of PET images using the wavelet transform

Unser, M.; Thevenaz, P.; Chulhee Lee; Ruttimann, U.E.;

Engineering in Medicine and Biology Magazine, IEEE , Volume: 14

Issue: 5 , Sept.-Oct. 1995

Page(s): 603 -611

[\[Abstract\]](#) [\[PDF Full-Text \(1216 KB\)\]](#) **IEEE JNL**

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object presence in the scene the orthophoto **difference image** contains a characteristic structure, which way of background surface model acquisition is **least square** method of fitting to the data set of points, www.dcs.gla.ac.uk/~sibiryaa/.Paper_Amsterdam1.pdf

[Robust Estimation of Camera Parameters Pan, Tilt and Zoom for.. - Broszio, Grau \(1999\) \(Correct\)](#)

to each pixel of the image $n \setminus \Gamma$. The **image difference** between the transformed image and the n th displacements based on residual analysis in a **least square** approach that computes the camera parameters. ftp.tnt.uni-hannover.de/pub/papers/1999/IWSNHC3D199-HBOG.ps.gz

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